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Addition/Correction

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Correction to Plasma-Enhanced Atomic Layer Deposition of Nanoscale Yttria-Stabilized Zirconia Electrolyte for Solid Oxide Fuel Cells with Porous Substrate

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P 3000. The grazing incidence XRD pattern in the original Figure 3c shows that polycrystalline YSZ thin film is grown

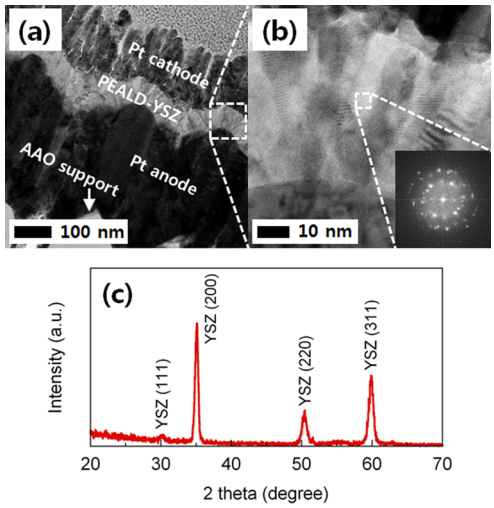

Figure 3. (a) High-resolution transmission electron microscopy cross-sectional images of an AAO-supported cell comprised of 70 nm PEALD-YSZ electrolyte, 320 nm Pt anode and 200 nm Pt cathode; (b) local diffraction pattern of the 70 nm PEALD-YSZ electrolyte (inset); (c) grazing-incidence X-ray diffraction pattern of 200 nm PEALD-YSZ on a Si (100) substrate.

on a Si (100) substrate by the PEALD process, but accidently the directional information on notable XRD peaks was marked with the same plane of YSZ (200). The directional information on XRD peaks positioned at approximately 30, 35, 51, and 60°, respectively, corresponds with the YSZ (111), YSZ (200), YSZ (220), and YSZ (311) planes. The corrected Figure 3 including Figure 3c with proper XRD peak information is presented. The interpretation of the results and conclusions of the paper are not affected by this erratum. The authors truly apologize for having misled and confused the readers.

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